


<b>Search Notes</b>  	<b>Application/Control No.</b>  10588631	<b>Applicant(s)/Patent Under Reexamination</b>  DENOMME, GREGORY A.
	<b>Examiner</b>  Young J Kim	<b>Art Unit</b>  1637

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
STIC-assisted search of SEQ ID Numbers 3 and 4 in commercial, issued-patent, and pre-grant patent publication databases	2/24/2009	/YJK/
search parameters: standard cDNA search and size-limited oligomer search (word size max = 30)	2/24/2009	/YJK/
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	2/24/2009	/YJK/
see enclosed for text-search strategy	2/24/2009	/YJK/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/Young J Kim/ Primary Examiner.Art Unit 1637
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